

測試報告 Test Report

號碼(No.): CE/2007/91300

日期(Date): 2007/09/13

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KEMET ELECTRONICS CORPORATION
P.O. BOX 5928, GREENVILLE, S.C. 29606



以下測試樣品係由客戶送樣，且由客戶聲稱並經客戶確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

樣品名稱(Sample Description) : KEMET SURFACE MOUNT CAPACITOR LEADFRAME
樣品型號(Style/Item No.) : T49X, T510, T52X, A700, T53X SERIES
收件日期(Sample Receiving Date) : 2007/09/06
測試期間(Testing Period) : 2007/09/06 TO 2007/09/13

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測試需求(Test Requested) : 參照 RoHS 2002/95/EC 及其修定指令要求. (In accordance with the RoHS Directive 2002/95/EC, and its amendment directives).
測試方法(Test Method) : 參考 IEC 62321, Ed. 1 111/54/CDV 方法檢測. (With reference to IEC 62321, Ed.1 111/54/CDV. Procedures for the Determination of Levels of Regulated Substances in Electrotechnical Products).
(1) 用感應耦合電漿原子發射光譜儀檢測鎘含量. / Determination of Cadmium by ICP-AES.
(2) 用感應耦合電漿原子發射光譜儀檢測鉛含量. / Determination of Lead by ICP-AES.
(3) 用感應耦合電漿原子發射光譜儀檢測汞含量. / Determination of Mercury by ICP-AES.
(4) 針對金屬材質之樣品，用 Spot test / Colorimetric 方法檢測六價鉻含量. / Determination of Hexavalent Chromium for metallic samples by Spot test / Colorimetric Method.
測試結果(Test Results) : 請見下一頁 (Please refer to next pages).

Chenyu Kung / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory – Taipei

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測試結果(Test Results) 單位(Unit): mg/kg

測試項目 (Test Items)	測試方法 Method (Refer to)	結果 (Result)	方法偵測 極限值 (MDL)
		No.1	
鎘 / Cadmium (Cd)	(1)	n.d.	2
鉛 / Lead (Pb)	(2)	18	2
汞 / Mercury (Hg)	(3)	n.d.	2
六價鉻 / Hexavalent Chromium Cr(VI) by Spot test / boiling water extraction	(4)	Negative	See Note 4

測試部位描述 (TEST PART DESCRIPTION):

NO.1 : 銀色/霧面銀色金屬 (SILVER COLORED/FROSTED-SILVER COLORED METAL)

備註(Note):

1. mg/kg = ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. Spot-test:

Negative = Absence of Cr(VI) coating / surface layer(鍍層中偵測不到六價鉻),
Positive = Presence of Cr(VI) coating / surface layer(鍍層中偵測到六價鉻);
The tested sample should be further verified by boiling-water-extraction method if the spot test result cannot be confirmed.

(當該測項無法確認時, 測試樣品可藉由boiling-water-extraction測試方法進一步確認)

Boiling-water-extraction:

Negative = Absence of Cr(VI) coating / surface layer(鍍層中偵測不到六價鉻),
Positive = Presence of Cr(VI) coating / surface layer(鍍層中偵測到六價鉻);
the detected concentration in boiling-water-extraction solution is equal or greater than 0.02 mg/kg with 50 cm² sample surface area.

該溶液濃度 ≥ 0.02 mg/kg with 50 cm² (sample surface area)

5. 樣品的測試是基於申請人要求混合測試, 報告中的混合測試結果不代表其中個別單一材質的含量.
(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing.
The above results was/were only given as the informality value).

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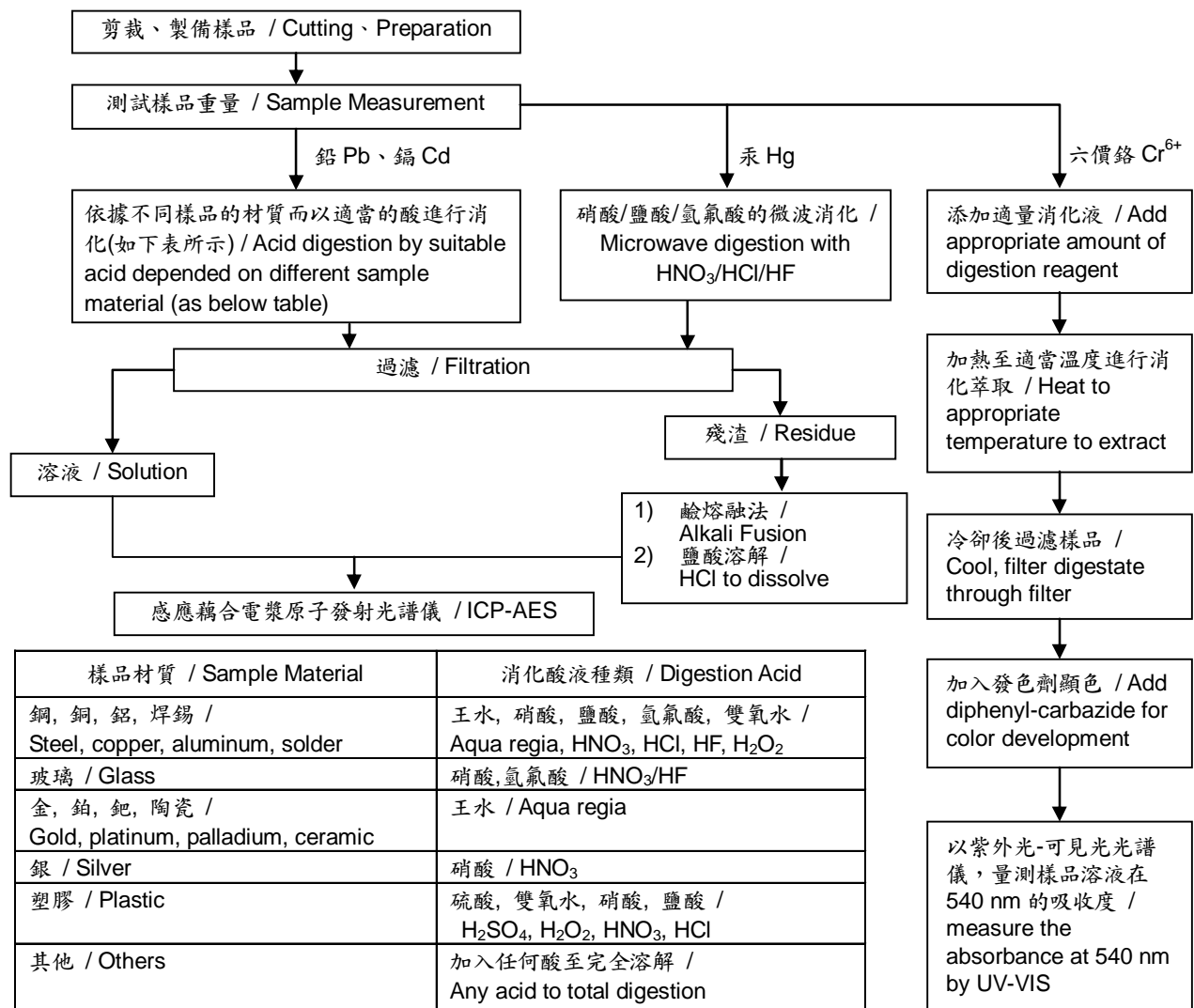
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- 1) 根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員：張啓興 / Name of the person who made measurement: Troy Chang
- 3) 測試負責人：龔振裕 / Name of the person in charge of measurement: Chenyu Kung



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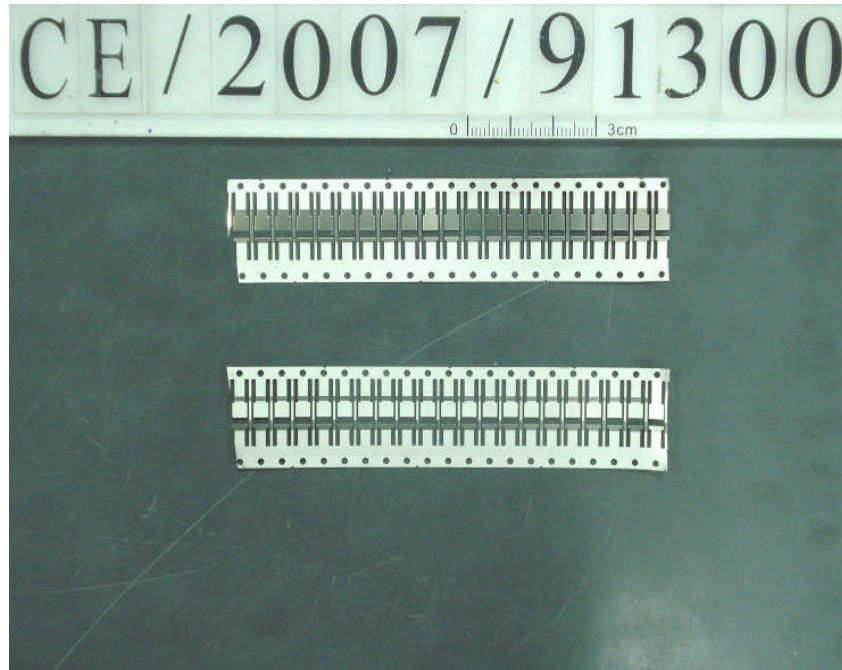
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** 報告結尾 **